

PATENT NUMBER

U.S. UTILITY Patent Application

O.I.P.E. TR SCANNED O.A.	PATENT DATE 1973
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APPLICATION NO.	CONT/PRIOR	CLASS	SUBCLASS	ART UNIT	EXAMINER
09/784626		250	559.4	2878 2882	Le S. N. G.

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Laser/scanning wafer inspection using nonlinear optical phenomena

PTO-2040
12/89

ISSUING CLASSIFICATION					
ORIGINAL		CROSS REFERENCE(S)			
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS WITH CROSS)		
INTERNATIONAL CLASSIFICATION					

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DRAWINGS		ISSUE BATCH NUMBER	
Sheet Drawing	Fig. Drawing	Print Fig.	Year Class
(Actual Exhibit)		(Date)	
(Primary Exhibit)		(Date)	
<input type="checkbox"/> The entire _____ method of _____ has been disclosed.			
(Legal Instrument Exhibit)		(Date)	

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